TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel IGBT

# GT10J321

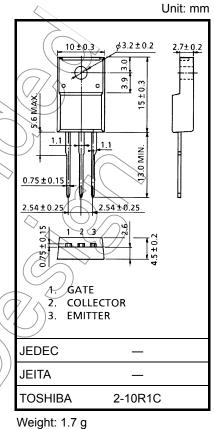
### High Power Switching Applications

**Fast Switching Applications** 

- Fourth-generation IGBT
- Enhancement mode type
- Fast switching (FS): Operating frequency up to 50 kHz (reference)
- High speed:  $t_f = 0.03 \ \mu s$  (typ.)
- Low switching loss : E<sub>on</sub> = 0.26 mJ (typ.) : E<sub>off</sub> = 0.18 mJ (typ.)
- Low saturation voltage: VCE (sat) = 2.0 V (typ.)
- FRD included between emitter and collector

#### Absolute Maximum Ratings (Ta = 25°C)

	•		,	$\left[ \left( \right) \right] $	_
Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage		V <sub>CES</sub>	600	∕∕y	
Gate-emitter voltage		V <sub>GES</sub>	<b>∌</b> 25	> v	
Continuous Collector current	@ Tc = 100°C	IC -	5	Ā	
	@ Tc = 25°C		10	~	
Pulsed collector current		I <sub>CP</sub>	( <u>20</u>	A	$\backslash$
Diode forward current	DC	I <sub>F</sub>	10	$\langle \langle \rangle$	$\backslash$
	Pulsed	IFP	20	R	
Collector power dissipation	@ Tc = 100°C	PG	)) 11	w	$\leq$
	@ Tc = 25°C		29 <		Ť
Junction temperature		$( _{\mathbf{I}_{j}} ) $	150	)%C	
Storage temperature range		Tstg	-55~150	°C	
					-



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

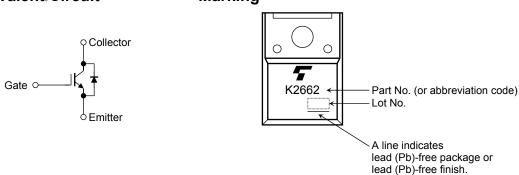
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Thermal Characteristics**

Characteristics		Symbol	Max	Unit
Thermal resistance (IGBT)	$\bigcirc$	R <sub>th</sub> (j-c)	4.31	°C/W
Thermal resistance (diode)	$\langle \rangle$	R <sub>th</sub> (j-c)	4.90	°C/W

#### **Equivalent Circuit**

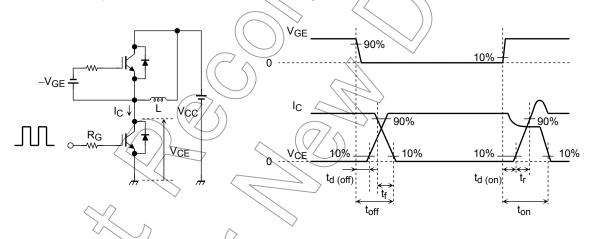




**Electrical Characteristics (Ta = 25°C)** 

Cha	racteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I <sub>GES</sub>	$V_{GE}=\pm 25~V,~V_{CE}=0$			±500	nA
Collector cut-off	current	ICES	$V_{CE} = 600 \text{ V}, \text{ V}_{GE} = 0$			1.0	mA
Gate-emitter cu	t-off voltage	V <sub>GE (OFF)</sub>	$I_C = 1 \text{ mA}, V_{CE} = 5 \text{ V}$	3.5	_	6.5	V
Collector-emitte	r saturation voltage	V <sub>CE (sat)</sub>	$I_{C} = 10 \text{ A}, \text{ V}_{GE} = 15 \text{ V}$	$\langle \rangle$	2.0	2.45	V
Input capacitant	ce	Cies	$V_{CE} = 10 \text{ V}, \text{ V}_{GE} = 0, \text{ f} = 1 \text{ MHz}$	Æ	) 1550	_	pF
Switching time	Turn-on delay time	t <sub>d (on)</sub>	. (7	$\sum$	0.06	_	
	Rise time	tr		$\mathcal{Y}$	0.03		μs
	Turn-on time	t <sub>on</sub>	Inductive load $V_{CC} = 300 \text{ V}, \text{ I}_{C} = 10 \text{ A}$		0.17		
	Turn-off delay time	<sup>t</sup> d (off)		_	0.24	_	
	Fall time	t <sub>f</sub>	$V_{GG} = +15 \text{ V}, \text{ R}_{G} = 68 \Omega$	—	0.03	$\rightarrow$	
	Turn-off time	t <sub>off</sub>	(Note 1)		0.30	>	
Switching loss	Turn-on switching loss	E <sub>on</sub>	(Note 2)	~((	0.26	) —	mJ
	Turn-off switching loss	E <sub>off</sub>			0.18		
Peak forward vo	oltage	VF	$I_F = 10 \text{ A}, V_{GE} = 0$	Ð	_	2.0	V
Reverse recove	ry time	t <sub>rr</sub>	$I_F = 10 \text{ A, } di/dt = -100 \text{ A/}\mu\text{s}$	-	100		ns

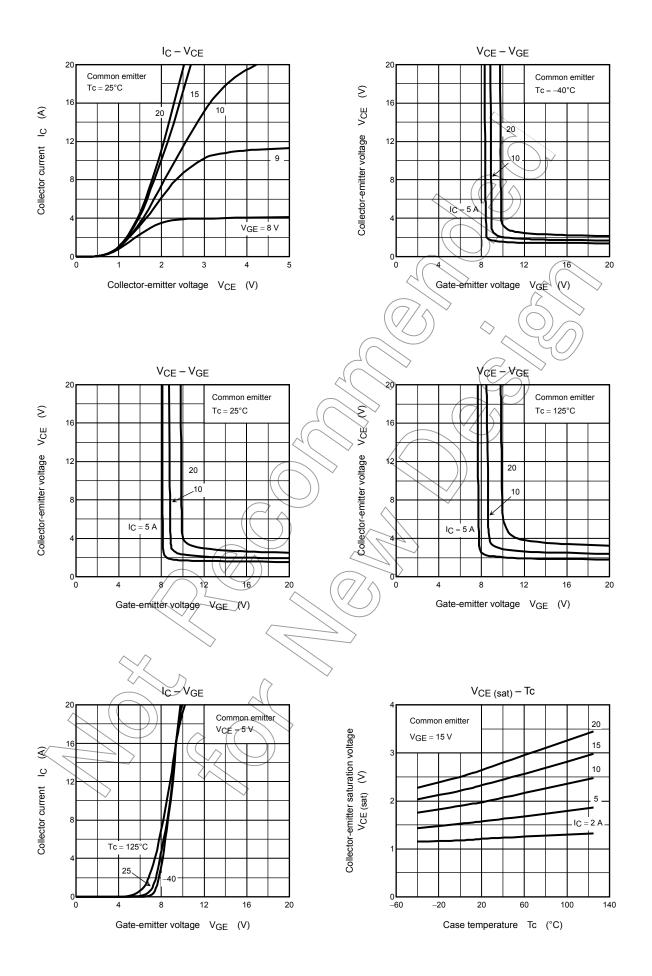
Note 1: Switching time measurement circuit and input/output waveforms

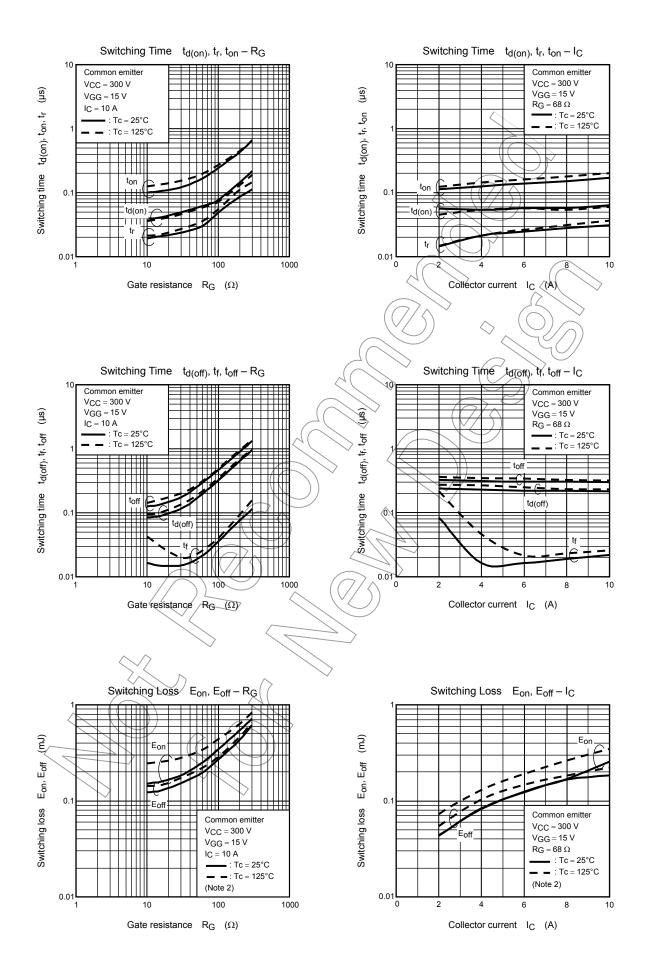


 $V_{CE}$  90% 10%

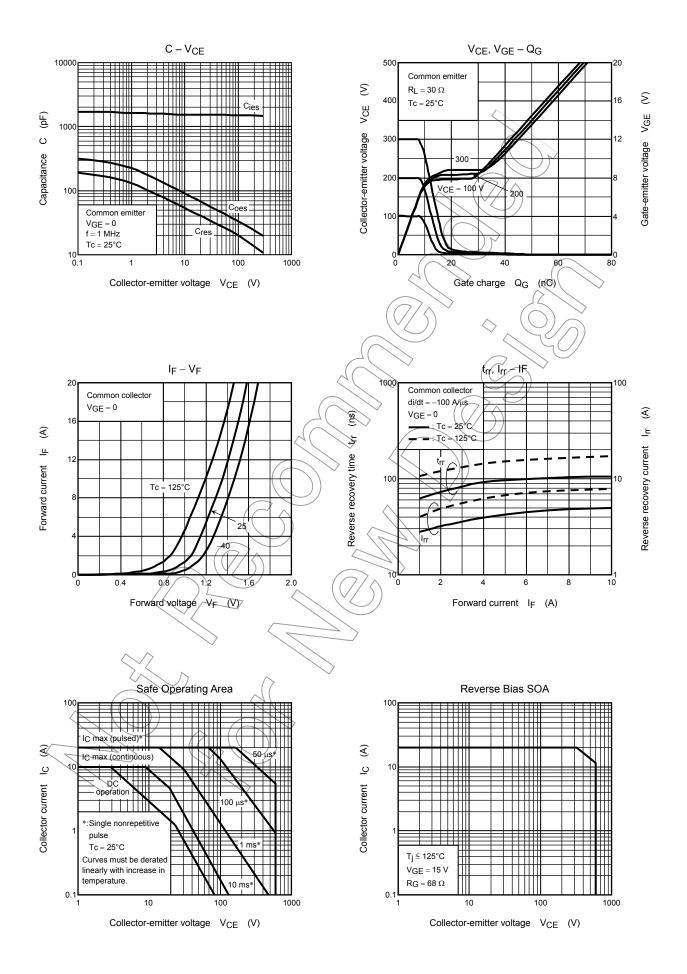
Note 2: Switching loss measurement waveforms

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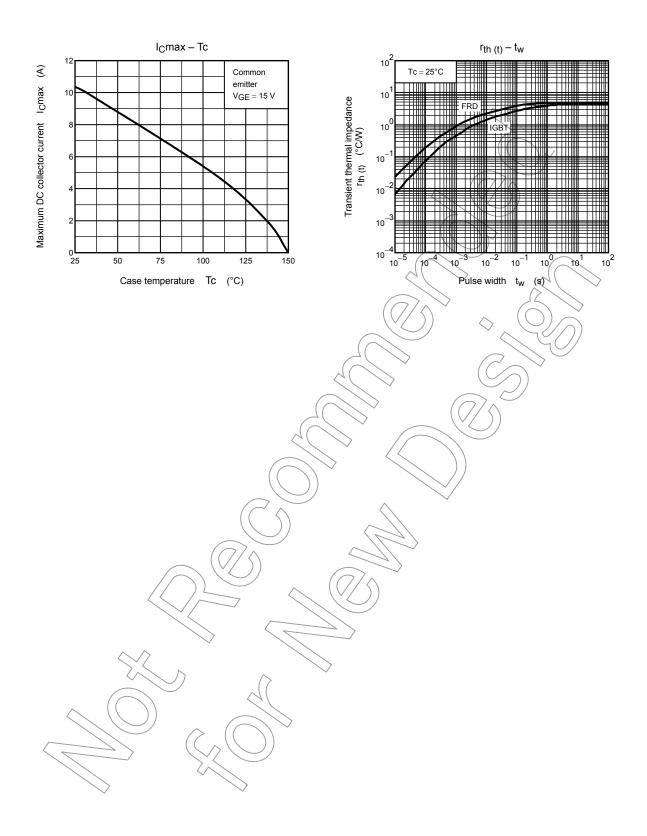




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Handbook" etc.

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